

# CA5470

# Quad, 14MHz, Microprocessor BiMOS-E Operational Amplifier with MOSFET Input/Bipolar Output

November 1996

### Features

- High Speed CMOS Input Stage Provides
  - Very High Z<sub>I</sub>.....5TΩ (5 x 10<sup>12</sup>Ω) (Typ)
  - Very Low II..... 0.5pA (Typ) at 5V Operation
  - Very Low I<sub>IO</sub> ..... 0.5pA (Typ) at 5V Operation
- ESD Protection to 2000V
- 3V to 16V Power Supply Operation
- Fully Guaranteed Specifications Over Full Military Range
- Wide BW (14MHz); High SR (5V/µs) at 5V Supply
- Wide V<sub>ICR</sub> Range From -0.5V to 3.7V (Typ) at 5V Supply
- Ideally Suited for CMOS and HCMOS Applications

#### Applications

- Bar Code Readers
- Photodiode Amplifiers (IR)
- Microprocessor Buffering
- Ground Reference Single Supply Amplifiers
- Fast Sample and Hold
- Timers
- Voltage Controlled Oscillators
- Voltage Followers
- V to I Converters
- Peak Detectors
- Precision Rectifiers
- 5V Logic Systems
- 3V Logic Systems

#### Pinout



## Description

The CA5470 is an operational amplifier that combines the advantages of both high speed CMOS and bipolar transistors on a single monolithic chip. It is constructed in the BiMOS-E process which adds drain-extension implants to  $3\mu$ m polygate CMOS, enhancing both the voltage capability and providing vertical bipolar transistors for broadband analog/digital functions. This process lends itself easily to high speed operational amplifiers, comparators, analog switches and interface peripherals, resulting in twice the speed of the conventional CMOS transistors having similar feature size.

BiMOS-E are broadbased bipolar transistors that have high transconductance, gains more constant with current level, stable "precision" base-emitter offset voltages and superior drive capability. Excellent interface with environmental potentials enable use in 5V logic systems and future 3.3V logic systems. Refer to Application Note AN8811.

ESD capability exceeds the standard 2000V level. The CA5470 series can operate with single supply voltages from 3V to 16V or  $\pm$ 1.5V to  $\pm$ 8V. They have guaranteed specifications at both 5V and  $\pm$ 7.5V at room temperature as well as over the full -55°C to 125°C military range.

#### **Ordering Information**

PART NUMBER (BRAND)	TEMP. RANGE ( <sup>o</sup> C)	PACKAGE	PKG. NO.
CA5470E	-55 to 125	14 Ld PDIP	E14.3
CA5470M (5470)	-55 to 125	14 Ld SOIC	M14.15
CA5470M96 (5470)	-55 to 125	14 Ld SOIC Tape and Reel	M14.15

#### **Absolute Maximum Ratings**

DC Supply Voltage (Between V+ And V- Terminals) 16V
Differential Input Voltage
Input Voltage
Input Current
Output Short Circuit Duration (Note 1) Indefinite

#### **Operating Conditions**

Temperature Range  $\ldots \ldots \ldots \ldots \ldots \ldots ... -55^oC$  to  $125^oC$ 

#### **Thermal Information**

Thermal Resistance (Typical, Note 1)	$\theta_{JA}$ ( <sup>o</sup> C/W)
PDIP Package	80
SOIC Package	175
Maximum Junction Temperature (Die)	
Maximum Junction Temperature (Plastic Package)	150 <sup>0</sup> C
Maximum Storage Temperature Range65	5 <sup>o</sup> C to 150 <sup>o</sup> C
Maximum Lead Temperature (Soldering 10s)	300 <sup>0</sup> C
(SOIC - Lead Tips Only)	

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

#### NOTES:

1. Short circuit may be applied to ground or to either supply.

2.  $\theta_{JA}$  is measured with the component mounted on an evaluation PC board in free air.

Electrical Specifications	Typical Values Intended Only for Desig	gn Guidance at V+ = 5V, V- = 0V, T	$_{A} = 25^{\circ}$ C, Unless Otherwise Specified
---------------------------	--	------------------------------------	---

PARAMETER	SYMBOL	TEST CONDITIONS	TYPICAL VALUES	UNITS
Input Resistance	RI		5	TΩ
Input Capacitance	Cl	f = 1MHz	3.1	pF
Unity Gain Crossover Frequency	fT		14	MHz
Slew Rate	SR	$V_{OUT} = 3.65 V_{P-P}$	5	V/µs
Transient Response: Rise Time/Fall Time	tr	$C_L = 25pF, R_L = 2k\Omega$ (Voltage Follower)	27/25	ns
Overshoot	OS	]	20	%
Settling Time (To <0.1%, $V_{IN} = 4V_{P-P}$ )	t <sub>S</sub>	$C_L = 25 pF, R_L = 2k\Omega$ (Voltage Follower)	1	μs
Full Power BW, SR = 5V/μs	FPBW	A <sub>V</sub> = 1, V <sub>OUT</sub> = 3.65V <sub>P-P</sub>	436	kHz

#### Electrical Specifications T<sub>A</sub> = 25°C, V+ = 5V, V- = GND

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Input Offset Voltage	V <sub>IO</sub>		-	6	22	mV
Input Offset Current	II <sub>IO</sub>		-	0.5	50 (Note 3)	pА
Input Current	l, li		-	0.5	50 (Note 3)	pА
Common Mode Input Range	V <sub>ICR</sub>		3.5	-0.5 to 3.7	0	V
Common Mode Rejection Ratio	CMRR	V <sub>ICR</sub> = 0V to 3.5V	55	70	-	dB
Power Supply Rejection Ratio	PSRR	$\Delta V = 2V$	60	75	-	dB
Positive Output Voltage Swing	V <sub>OM</sub> +	$R_L = 2k\Omega$ to GND	4	4.4	-	V
Negative Output Voltage Swing	V <sub>OM</sub> -	$R_L = 2k\Omega$ to GND	-	0.06	0.10	V
Total Supply Current	I <sub>SUPPLY</sub>	$V_{OUT} = 2.5V, R_{L} = \infty$	-	6	7	mA
Unity Gain Bandwidth Product	fT		10	14	-	MHz
Slew Rate	SR		4	5	-	V/µs
Output Current						
Source to opposite supply	ISOURCE		4	5.5	-	mA
Sink to opposite supply	I <sub>SINK</sub>	1	1.0	1.2	-	mA
Open Loop Gain	A <sub>OL</sub>	0.5V to 3.5V, $R_L = 10k\Omega$	80	90	-	dB

NOTE:

3. This is the lowest value that can be tested reliably. Almost all devices will be <10pA.

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Input Offset Voltage	V <sub>IO</sub>		-	6	25	mV
Input Offset Current	lliol		-	550	5500	pА
Input Current	Ц		-	550	11000	pА
Common Mode Input Range	V <sub>ICR</sub>		3.5	-0.5 to 3.7	0	V
Common Mode Rejection Ratio	CMRR	V <sub>ICR</sub> = 0V to 3.5V	50	65	-	dB
Power Supply Rejection Ratio	PSRR	$\Delta V = 2V$	58	75	-	dB
Positive Output Voltage Swing	V <sub>OM</sub> +	$R_L = 2k\Omega$ to GND	3.8	4.2	-	V
Negative Output Voltage Swing	V <sub>OM</sub> -	$R_L = 2k\Omega$ to GND	-	0.08	0.11	V
Total Supply Current	ISUPPLY	V <sub>OUT</sub> = 2.5V	-	9	11	mA
Unity Gain Bandwidth Product	fT		8	12	-	MHz
Slew Rate	SR		3	5	-	V/μs
Output Current						
Source to opposite supply	ISOURCE		4	5.5	-	mA
Sink to opposite supply	I <sub>SINK</sub>	7 1	0.8	1.2	-	mA
Open Loop Gain	A <sub>OL</sub>	0.5V to 3.5V, $R_L = 10k\Omega$	80	90	-	dB
Electrical Specifications T, PARAMETER	A = 25°C, V <sub>SUPPL</sub>	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Input Offset Voltage	V <sub>IO</sub>		-	5	25	mV
Input Offset Current	I <sub>IO</sub>		-	0.5	50 (Note 4)	pА
Input Current	lį		-	1	50 (Note 4)	pА
Common Mode Input Range	VICR		5.8	-7.8 to 6.0	-7.5	V
Common Mode Rejection Ratio	CMRR	V <sub>ICR</sub> = 0V to 13.3V	60	70	- 1	dB
Power Supply Rejection Ratio	PSRR	$\Delta V = 1V$	60	76	- 1	dB
Positive Output Voltage Swing	V <sub>OM</sub> +					
		$R_L = 2k\Omega$ to GND	6.3	6.5		V
		$R_{\rm L} = 10 k\Omega$ to GND	6.4	6.6	-	V
Negative Output Voltage Swing	V <sub>OM</sub> -					•
	· UIVI	$R_{I} = 2k\Omega$ to GND	-	-2.6	-2	V
		$R_{\rm L} = 10 k\Omega$ to GND	_	-7.3	-7.1	V
Total Supply Current	le	$V_{OUT} = GND, R_L = \infty$	-	-7.3	-7.1	
,		vout = 0ind, kL = ∞		_		mA
Unity Gain Bandwidth Product	f <sub>T</sub>		12	16	-	MHz
Slew Rate	SR		4	7	-	V/µs
Output Current						
Source to opposite supply	ISOURCE	[	6.2	6.8	-	mA
Sink to opposite supply	I <sub>SINK</sub>		1	1.4	-	mA

NOTE:

4. This is the lowest value that can be tested reliably. Almost all devices will be <10pA.

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Input Offset Voltage	V <sub>IO</sub>		-	5	30	mV
Input Offset Current	I <sub>IO</sub>		-	550	5500	pА
Input Current	lı		-	1100	11000	pА
Common Mode Input Range	V <sub>ICR</sub>		5.8	-7.8 to 6.0	-7.5	V
Common Mode Rejection Ratio	CMRR	V <sub>ICR</sub> = 0V to 3.5V	58	70	-	dB
Power Supply Rejection Ratio	PSRR	$\Delta V = 1V$	60	76	-	dB
Positive Output Voltage Swing	V <sub>OM</sub> +					
		$R_L = 2k\Omega$ to GND	4.75	5.5	-	V
		$R_L = 10k\Omega$ to GND	6.1	6.4	-	V
Negative Output Voltage Swing	V <sub>OM</sub> -					
		$R_L = 2k\Omega$ to GND	-	-2.6	-2	V
		$R_L = 10k\Omega$ to GND	-	-7.3	-7.1	V
Total Supply Current	ISUPPLY	$V_{OUT} = GND, R_L = \infty$	-	12	18	mA
Unity Gain Bandwidth Product	f <sub>T</sub>		10	15	-	MHz
Slew Rate	SR		3	7	-	V/µs
Output Current						
Source to opposite supply	ISOURCE		6.2	6.8	-	mA
Sink to opposite supply	I <sub>SINK</sub>	1	1	1.4	-	mA
Open Loop Gain	A <sub>OL</sub>	-5V to +5V, $R_1 = 10k\Omega$	80	90	-	dB

**Electrical Specifications**  $T_A = -55^{\circ}C$  to  $125^{\circ}C$ ,  $V_{SUPPLY} = \pm 7.5V$ 

# Block Diagram (1/4 of CA5470)







Dimensions in parentheses are in millimeters and derived from the basic inch dimensions as indicated. Grid graduations are in mils  $(10^{-3} \text{ inch})$ .

The layout represents a chip when it is part of the wafer. When the wafer is cut into chips, the cleavage angles are  $57^{\circ}$  instead of  $90^{\circ}$  with respect to the face of the chip. Therefore, the isolated chip is actually 7 mils (0.17mm) larger in both dimensions.

